



This 19,999-count L/C/R hand-held meter is a special microprocessor-controlled meter for measuring functions of inductance, capacitance and resistance. Simple to operate, the instrument not only takes absolute parallel mode measurements, but also capable of series mode measurement. The meter provides direct and accurate measurements of inductors, capacitors and resistors with different testing frequencies. It is selectable for auto and manual ranging.

| | |
|---|--|
| Parameters measured | L/C/R/D/Q. |
| Measuring circuit mode | |
| Inductance (L) | Defaults to series mode |
| Capacit./Resist. (C/R) | Defaults to parallel mode. |
| Displays | L/C/R: Maximum display 19999 D/Q: Maximum display 999 (Auto Range) |
| Ranging mode | Auto & Manual. |
| Measuring terminals | 3 terminals with sockets. |
| Test frequency | 1 KHz, 120 Hz \pm 0,1% |
| Tolerance mode | 1%, 5%, 10%. |
| Test signal level | 0.6 Vrms approx. |
| Measuring rate | 1 measure/second, nominal |
| Response time | Approx. 1 second at manual range |
| Auto power-off | 5 minutes approx. without operation |
| Temperature coefficient | 0.15 x (specified accuracy) / °C (0-18 °C and 28-40 °C) |
| Operating environmental conditions | |
| Altitude | Up to 2000 m |
| Temperature range | From 0 °C to 40 °C |
| Max. relative humidity | 80 % (up to 31 °C), decreasing lineally up to 50% at 40 °C |
| Low battery indication | Approx. 6.8 V |
| Power consumption | Approx. 40 mA for operation / 0.08 mA after Auto Power-off |
| Power requirements | 1.- DC 9V battery 2.- Ext. DC Adaptor: DC 12 Vmin-15 Vmax (load 50 mA Min.) |
| Input protection | Fuse |

| | |
|-----------------------------|--|
| Standard accessories | Test alligator clips (pair) DC 9V battery User manual |
| Optional accessories | Carrying case DC-231 RS232 package RM-505B SMD Tweezers PP-009 DC Adapter (230 V AC) AL013 |
| Dimensions (L/W/H) | 184 / 87 / 41 mm |
| Weight | 330 grams |

RANGES AND ACCURACIES

Accuracy \pm (% of reading \pm num. of digits) at 23°C \pm 5°C, RH<75%.

Resistance (parallel mode)

Test Frequency: 120 Hz / 1 KHz

| Range | Maximum Display | Accuracy | | Specified Note |
|----------------|------------------|----------------------------|----------------------------|------------------|
| | | at 120 Hz | at 1 KHz | |
| 10 M Ω | 9.999 M Ω | 2.0%+8 dig. ⁽¹⁾ | 2.0%+8 dig. ⁽¹⁾ | After open cal. |
| 2000K Ω | 1999.9k Ω | 0.5%+5 dig. | 0.5%+5 dig. | After open cal. |
| 200K Ω | 199.99k Ω | 0.5%+3 dig. | 0.5%+3 dig. | - |
| 20K Ω | 19.999k Ω | 0.5%+3 dig. | 0.5%+3 dig. | - |
| 2000 Ω | 1999.9 Ω | 0.5%+3 dig. | 0.5%+3 dig. | - |
| 200 Ω | 199.99 Ω | 0.8%+5 dig. | 0.8%+5 dig. | After short cal. |
| 20 Ω | 19.999 Ω | 1.2%+40 dig. | 1.2%+40 dig. | After short cal. |

Notes: This specification is based on the measurement performed at the test socket.
DUT (Device Under Test) & Test leads should be properly shielded to GUARD if a greater measurement accuracy is necessary.

⁽¹⁾ This specification is based on battery operation.

Capacitance (parallel mode)

Test Frequency: 120 Hz

| Range | Maximum Display | Accuracy | | Specified Note |
|--------------|-------------------------------|----------------------|-----------------------------|------------------|
| | | Capacity. | DF | |
| 10mF | 19.99mF ⁽²⁾ | 3.0%+5 dig. (DF<0.1) | 10%+100/Cx+5 dig. (DF<0.1) | After short cal. |
| 1000 μ F | 1999.9 μ F ⁽³⁾ | 1.0%+5 dig. (DF<0.1) | 2%+100/Cx+5 dig. (DF<0.1) | After short cal. |
| 200 μ F | 199.99 μ F | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 20 μ F | 19.999 μ F | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 2000nF | 1999.9nF | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 200nF | 199.99nF | 0.7%+5 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | After open cal. |
| 20nF | 19.999nF | 1.0%+5 dig. (DF<0.1) | 2%+100/Cx+5 dig. (DF<0.1) | After open cal. |

Test Frequency: 1 KHz

| Range | Maximum Display | Accuracy | | Specified Note |
|-------------|-------------------------------|----------------------|-----------------------------|------------------|
| | | Capacity. | DF | |
| 1mF | 1.999mF ⁽²⁾ | 3.0%+5 dig. (DF<0.1) | 10%+100/Cx+5 dig. (DF<0.1) | After short cal. |
| 200 μ F | 199.99 μ F ⁽³⁾ | 1.0%+5 dig. (DF<0.1) | 2.0%+100/Cx+5 dig. (DF<0.1) | After short cal. |
| 20 μ F | 19.999 μ F | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 2000nF | 1999.9nF | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 200nF | 199.99nF | 0.7%+3 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | - |
| 20nF | 19.999nF | 0.7%+5 dig. (DF<0.5) | 0.7%+100/Cx+5 dig. (DF<0.5) | After open cal. |
| 2000pF | 1999.9pF | 1.0%+5 dig. (DF<0.1) | 2.0%+100/Cx+5 dig. (DF<0.1) | After open cal. |

Notes: Q Value is the reciprocal of DF (dissipation factor).
 This specification is based on the measurement performed at the test socket.
 DUT (Device Under Test) & Test leads should be properly shielded to GUARD if a greater measurement accuracy is necessary.
 Cx=Counts of displayed C value, e.g. C=88.88 μ F then Cx=8888.

- (2) This reading can be extended to 1999 MAX display with accuracy not specified.
 (3) This reading can be extended to 19999 MAX display with accuracy not specified.

Inductance (series mode)

Test Frequency: 120 Hz

| Range | Maximum Display | Accuracy | | Specified Note |
|-------|-----------------|--------------------------|--------------------|------------------|
| | | Inductance | DF | |
| 1000H | 999.9H | 1.0%+ (Lx/10000)%+5 dig. | 2%+100/Lx+5 dig. | After open cal. |
| 200H | 199.99H | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 20H | 19.999H | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 2000m | 1999.9mH | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 200m | 199.99mH | 1.0%+ (Lx/10000)%+5 dig. | 3%+100/Lx+5 dig. | After short cal. |
| 20m | 19.999mH | 2.0%+ (Lx/10000)%+5 dig. | 10%+100/Lx+5 dig. | After short cal. |

Test Frequency: 1 KHz

| Range | Maximum Display | Accuracy | | Specified Note |
|--------------|-----------------|--------------------------|--------------------|------------------|
| | | Inductance | DF | |
| 100H | 99.99H | 1.0%+ (Lx/10000)%+5 dig. | 2.0%+100/Lx+5 dig. | After open cal. |
| 20H | 19.999H | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 2000mH | 1999.9mH | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 200mH | 199.99mH | 0.7%+ (Lx/10000)%+5 dig. | 1.2%+100/Lx+5 dig. | - |
| 20mH | 19.999mH | 1.0%+ (Lx/10000)%+5 dig. | 3.0%+100/Lx+5 dig. | After short cal. |
| 2000 μ H | 1999.9 μ H | 2.0%+ (Lx/10000)%+5 dig. | 10%+100/Lx+5 dig. | After short cal. |

Notes: Q Value is the reciprocal of DF.
 This specification is based on the measurement performed at the test socket.
 DUT (Device Under Test) & Test leads should be properly shielded to GUARD if a greater measurement accuracy is necessary.
 Lx=Counts of displayed L value, e.g. L=88.88H then Lx=8888.